**PATENT** 

Attorney Docket No.: AMAT/8338/DSM/LOW K/JW

Express Mail No.: EV335470113US

**ABSTRACT OF THE DISCLOSURE** 

A method for depositing an organosilicate layer on a substrate includes varying

one or more processing conditions during a process sequence for depositing an

organosilicate layer from a gas mixture comprising an organosilicon compound in the

presence of RF power in a processing chamber. In one aspect, the distance between

the substrate and a gas distribution manifold in the processing chamber is varied during

processing. Preferably, the method of depositing an organosilicate layer minimizes

plasma-induced damage to the substrate.

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